

<b>Notice of References Cited</b>	Application/Control No. 09/910,732	Applicant(s)/Patent Under Reexamination SCHRAMM, PETER	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,108,374	08-2000	Balachandran et al.	375/227
*	B	US-6,747,945	06-2004	Sudo et al.	370/203
*	C	US-6,690,680	02-2004	Marchok et al.	370/480
*	D	US-6,456,653	09-2002	Sayeed, Zulfiquar	375/227
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